SEM, TEM, STM Supplies

SEM Specimen Stubs

Short Pin Type

Aluminium

| 1⁄2" Ø (12.5 | 5mm) with 3.2mm Ø, 8mm long pin with groove for Cambi | ridge/LE | EO, Philips, Etec |
|--------------|--|----------|--------------------------------|
| etc instrum | ents. | | |
| S081 | 1/2" Pin type stub (with groove) | | pack of 100 |
| S081/1 | 1/2" Pin type stub (with groove) | | pack of 1000 |
| S081/HP | ¹ / ₂ " Pin type stub (with groove) <i>high purity AI</i> for analysis | apps | pack of 100 |
| S081/T | 1/2" Pin type sticky tab stub | | pack of 1000 |
| S081/T1 | 1/2" Pin type sticky tab stub | | pack of 100 |
| S182 | ½" Pin type stub (without groove) | | pack of 100 |
| S433 S434 | ¹ / ₂ " Pin type stub (with groove) Pin 3.2mm Ø, 6mm long ¹ / ₂ " Pin type stub (no groove) Pin 3.2mm Ø, 6mm long | for LE | O pack of 100 O pack of 100 |

Brass

| S178 | ¹ / ₂ " Pin type stub (with groove) | nack of 10 |
|------|---|------------|
| 31/0 | | pack of TU |

Copper

S179 $\frac{1}{2}$ " Pin type stub (with groove)

pack of 10

- 1" Ø (25.4mm) Aluminium Short Pin type stub with 3.2mm Ø, 8mm long pin for Cambridge/LEO and Philips instruments. S087 1" Pin type stub pack of 50
- **32mm** Ø Aluminium Short Pin type stub with 3.2mm Ø pin for Camscan S181 32mm Ø pin type stub pack of 50

Long Pin Type

Aluminium ¹/₂" Ø (12.5mm) with 3.2mm Ø pin 15mm long for Amray S180 1/2" Amray pin stub pack of 50

Re-entry Type

32mm (11/4") Ø re-entry (dish) type stub for Cambridge/LEO S091 32mm (11/4") Ø Aluminium re-entry type stub

pack of 50

Cylinder Type

Plain cylindrical aluminium stubs for JEOL instruments

S187 12.5mm Ø x 15mm high pck of 50 **S183** 10mm Ø x 3.5mm high pck of 50 **S082** 10mm Ø x 5mm high pck of 50 **S083** 10mm Ø x 10mm high pck of 50 S184 10mm Ø x 12.5mm high pck of 50 **S185** 12.5mm Ø x 5mm high pck of 50 **S186** 12.5mm Ø x 10mm high pck of 50

S189 50mm Ø x 10mm high pck of 50 **S084** 15mm Ø x 5mm high pck of 50 **S085** 15mm Ø x 10mm high pck of 50 **S086** 15mm Ø x 15mm high pck of 50 **S089** 32mm Ø x 5mm high pck of 50 **S090** 32mm Ø x 10mm high pck of 50 **S188** 32mm Ø x 20mm high pck of 50

Re-entry Type Stub Adapter

A simple, effective adapter to convert 12.5mm (1/2") pin stubs to allow 32mm (1.5") Ø re-entry dish type stubs to be used on $\frac{1}{8}$ stage. The ball catch gives a trouble free, quick solution to a difficult problem.

S261 SEM stub adapter - re-entry stub



S182

S081/S178/S179













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10 SEM, TEM, STM Supplies









Types S100/101



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Types S102/103/104/105



S106/107





Chamfered Type

Aluminium stubs with a chamfered angle of 45° suitable for **JEOL** or **ISI** instruments where fitting stages are not available.

| S127 | Angled stub 10mm Ø | pack of 10 |
|------|----------------------|------------|
| S190 | Angled stub 12.5mm Ø | pack of 10 |
| S126 | Angled stub 15mm Ø | pack of 10 |

Threaded Type

Aluminium stubs threaded with M4 female thread in base for **Hitachi** instruments.

| S128 | Threaded stub 15mm Ø x 6mm high | pack of 50 |
|------|----------------------------------|------------|
| S191 | Threaded stub 25mm Ø x 6mm high | pack of 50 |
| S192 | Threaded stub 32mm Ø x 2mm high | pack of 50 |
| S193 | Threaded stub 32mm Ø x 10mm high | pack of 50 |

Carbon Stubs

Where the background radiation from the specimen stub is troublesome, a specimen stub manufactured from spectroscopic carbon may be used. Stubs for **Cambridge/LEO**, **JEOL** and **ISI** microscopes are available. They can have a *standard* finish or an *ultra smooth* finish for small particles or fibres.

| S100 | Carbon stub for Cambridge/LEO standard finish | each |
|------|---|------|
| S101 | Carbon stub for Cambridge/LEO ultra smooth finish | each |
| S102 | Carbon stub for JEOL (10 Ø x 10mm H) standard | each |
| S103 | Carbon stub for JEOL (10 Ø x 10mm H) ultra smooth | each |
| S104 | Carbon stub for ISI (15mm Ø x 10mm H) standard | each |
| S105 | Carbon stub for ISI (15mm Ø x 10mm H) ultra smooth | each |
| S106 | Carbon stub for Cambridge microanalysis stage std | each |
| S107 | Carbon stub for Cambridge m/analysis stage u/smooth | each |
| | | |

Carbon Disc on Stub

This is an economical solution to the need for a light element surface for mounting specimens that are to be used for microanalysis. The carbon disc is 3mm thick and is glued to a standard $\frac{1}{2}$ " (12.5mm) stub.

Supplied in batches of 8 stubs in a stub storage box.

S111 Box of 8 carbon covered 1/2" (12.5mm) stubs

Beryllium Discs (Planchettes)

An alternative to carbon as a support for certain applications. Two types are available: **1)** 50µm Beryllium laminate on a copper support to give excellent price/performance. The laminate Be/Cu is thick enough to reduce background radiation to levels achieved by solid Be. In addition, the ductile Cu layer will inhibit fracture of the brittle Be.

D211 Be/Cu disc 1cm $\emptyset \ge 0.25$ mm thick **D212** Be/Cu disc 1.27cm $\emptyset \ge 0.25$ mm thick **D213** Be/Cu disc 2.5cm $\emptyset \ge 1.5$ mm thick

D214 Be/Cu disc 50.8mm Ø x 1mm thick **D215** Be/Cu disc 101.6mm Ø x 1mm thick **D216** Be/Cu disc 203.2mm Ø x 2mm thick

The above are also available with a *raised and numbered grid* for easy location in the SEM **D217** Be/Cu disc 1cm Ø x 0.25mm **D219** 2.5cm Ø x 1mm **D218** Be/Cu disc 1.27cm Ø x 0.25mm

 2) Solid beryllium discs 50µm thick
 D220 Be disc 10mm Ø
 D221 Be disc 12.5mm Ø
 D222 Be disc 25mm Ø